

L Number	Hits	Search Text	DB	Time stamp
1	1	(high adj voltage adj semiconductor adj device) and (high adj current) and (sufficient adj thickness) and metal	USPAT	2003/03/10 16:24
2	1	((high adj voltage adj semiconductor adj device) and (high adj current) and (sufficient adj thickness) and metal) and (interconnect or interconnection or metal or conductive or electrode or plurality or structure or device or carry or least or oxidized or slot or hole oe holes or contact or plug or ground or substrate or voltage or current or high)	USPAT	2003/03/10 16:28
3	1	("6008127").PN.	USPAT	2003/03/10 16:20
4	1	((("6008127").PN.) and (interconnect or interconnection or metal or conductive or electrode or plurality or structure or device or carry or least or oxidized or slot or hole oe holes or contact or plug or ground or substrate or voltage or current or high or semiconductor)	USPAT	2003/03/10 16:21
5	41	(high adj voltage) and (high adj current) and (sufficient adj thickness) and metal and device and semiconductor and conductive	USPAT	2003/03/10 16:25
6	0	(high adj voltage) and (high adj current) and (sufficient adj thickness) and metal and device and semiconductor and conductive and interconnection and slot	USPAT	2003/03/10 16:26
7	0	(high adj voltage) and (high adj current) and (sufficient adj thickness) and metal and device and semiconductor and conductive and interconnection and hole and plug	USPAT	2003/03/10 16:27
8	13	(high adj voltage) and (high adj current) and (sufficient adj thickness) and metal and device and semiconductor and conductive and interconnection and hole	USPAT	2003/03/10 16:27
9	13	((high adj voltage) and (high adj current) and (sufficient adj thickness) and metal and device and semiconductor and conductive and interconnection and hole) and (interconnect or interconnection or metal or conductive or electrode or plurality or structure or device or carry or least or oxidized or slot or hole oe holes or contact or plug or ground or substrate or voltage or current or high)	USPAT	2003/03/10 17:06
10	1	("5304508").PN.	USPAT	2003/03/10 17:07
11	1	("5258643").PN.	USPAT	2003/03/10 17:07
-	0	(least adj one adj metal adj3 sufficient adj thickness adj2 carry adj2 high adj current) and (high adj voltage) and (semiconductor adj device)	USPAT	2003/03/10 14:05
-	0	(least adj one adj metal adj3 sufficient adj thickness adj2 carry adj2 high adj current) and (high adj voltage)	USPAT	2003/03/10 14:03
-	0	(least adj one adj metal adj3 sufficient adj thickness adj2 carry adj2 high adj current) and (semiconductor adj device)	USPAT	2003/03/10 14:04
-	0	(least adj one adj metal adj4 thickness adj4 high adj current) and (high adj voltage) and (semiconductor adj device)	USPAT	2003/03/10 14:06
-	0	(least adj one adj metal adj5 thickness adj6 high adj current) and (high adj voltage) and (semiconductor adj device)	USPAT	2003/03/10 16:04

3/10/03